

FTI-2000

Power IC Test System

Focused Test, Inc. (FTI) was founded in August 2006, with the mission to apply a *'focused technology'* approach to the design of production testers for power discrete devices and analog IC's. Our goal is to offer a unique solution that meets our customers's need for low-cost test equipment targeting specific product segments. In this way, we provide the lowest acquisition cost and highest throughput, along with an impressive array of test engineering tools.



instrument modules, including a Quad VI and a Dual High Power Source. Additional channel boards can be easily added, depending on the required configuration, and each channel board is synchronized by a cabled 'Sync Bus'.

FTI 2000 can be easily configured to perform parallel tests with many different types of multisite handlers, including gravity, turret, strip and wafer ring handlers. FTI's highly flexible 'FTI Studio' software is Dot Net based and has a multi-threaded architecture which allows our testers to easily perform parallel tests in many different multisite test modes including Index Parallel, with no test-time penalty.



FTI 2000 Test System

The FTI 2000 analog IC tester utilizes FTI's 'Tester-per-Site' architecture based on the USB bus that allows easy system scalability for multisite applications. The tester consists of one or more channel boards each populated by up to four instrument modules. Each FTI 2000 channel board is equipped with a USB bus, and an FPGA for basic control, timing and digital test functions. The FTI 2000 channel board can be populated by a range of plug-in

In addition to best-in-class production test performance, the FTI 2000 also offers a feature-rich range of software engineering tools. These include a Parts Average Test (PAT) Tool that implements the AEC Q001 Rev C standard.

 ***FOCUSED TEST, INC.***



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TYPICAL APPLICATIONS:

- Voltage Regulators (LDO, Buck, PWM, DC-DC)
- Drivers (Line Drivers, LED Drivers/Charge Pumps, Mosfet Drivers)
- Analog Switches
- Temperature Sensors

TECHNICAL FEATURES:

- Tester-per-Site, USB System Bus Architecture
- Highly Scalable for Multisite Applications
- Quad VI - 40V, 40mA
- Dual Floating High Power Source - 10A
- TMU per Channel 20nS Resolution
- Digital Test to 12V Levels for Serial Bus (e.g. I²C), Serial Interfaces etc.
- Low Leakage Pico-Ammeter
- "TMT" ASL-1000 DUT Board Interface
- Low Cost, Small Footprint

DIMENSIONS (in cm) & POWER REQUIREMENTS:

- FTI-2000 Test Head (Dual Channel Board) - 15.5W x 53L x 34.5H
- External Power Supply Modules - 10W x 19.5L x 6H (one per channel board)
- Dell Desktop Tower - 19W x 44L x 41H
- Power Requirements - 110/220V single phase, 150W (per channel board)

For more information please send an email to: sales@focusedtest.com

FTI-2000 can be expanded for Multi-Site Testing by adding Multiple Channel Boards with Sync Bus

